Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/667,663	SHIRAISHI ET AL.	
Examiner	Art Unit	
Thien M. Le	2876	

	SEARCHED				
Class	Subclass	Date	Examiner		
235	492	6/22/2005	LTM		
	375				
	441				
	493				
	486				
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365	185.11				
	185.33				
707	100,200,2				

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
	1-			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
EAST		6/25/2005	LTM